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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>				Complete if Known	
				Application Number	10/596,626-Conf. #8534
				Filing Date	September 15, 2006
				First Named Inventor	Karl-Heinz Schuster
				Art Unit	2873
				Examiner Name	E. A. Lester
Sheet	1	of	14	Attorney Docket Number	01641/0204258-USO

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
		Number-Kind Code ² (if known)				
	AA*	US-2,380,887	07-01-1945	Warmishan		
	AB*	US-3,244,073	04-05-1966	Bouwers et al.		
	AC*	US-4,103,990	08-01-1978	Yamada et al.		
	AD*	US-4,241,390	12-23-1980	Markie et al.		
	AE*	US-4,293,186	10-06-1981	Offner		
	AF*	US-4,346,164	08-24-1982	Tabarelli et al.		
	AG*	US-4,398,809	08-16-1983	Canzek et al.		
	AH*	US-4,443,068	04-17-1984	Itoh et al.		
	AI*	US-4,469,414	09-04-1984	Shafer		
	AJ*	US-4,482,219	11-13-1984	Canzek et al.		
	AK*	US-4,666,259	05-19-1987	Iizuka et al.		
	AL*	US-4,685,777	08-11-1987	Hirose et al.		
	AM*	US-4,711,535	12-08-1987	Shafer		
	AN*	US-4,757,354	07-12-1988	Sato et al.		
	AO*	US-4,779,966	10-25-1988	Friedman		
	AP*	US-4,812,028	03-14-1989	Matsumoto et al.		
	AQ*	US-4,834,515	05-30-1989	Mercado		
	AR*	US-4,951,078	08-21-1990	Okada et al.		
	AS*	US-5,004,331	04-02-1991	Haselline et al.		

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Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	f*
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	MM-DD-YYYY			
	BA	CN-1802726-A	07-12-2006	Nippon Kogaku Kk		✓
	BB	DE-19633128-A1	02-19-1998	Zeiss Carl Fa		✓
	BC	DE-10123725-A1	11-21-2002	Zeiss Carl		✓
	BD	DE-10332112-A1	01-27-2005	Zeiss Carl Smt Ag		✓
	BE	DE-102005056721-A1	11-09-2006	Zeiss Carl Smt Ag		✓
	BF	EP-0267766-A2	05-18-1988	Compact Spindle Bearing Corp		

Examiner Signature		Date Considered	
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		Number-Kind Code ² (if known)			
	AT*	US-5,031,976	07-16-1991	Shafer	
	AU*	US-5,063,586	11-05-1991	Jewell et al.	
	AV*	US-5,114,238	05-19-1992	Sigler	
	AW*	US-5,121,256	06-09-1992	Corle et al.	
	AX*	US-5,153,898	10-06-1992	Suzuki et al.	
	AY*	US-5,212,588-B1	05-18-1993	Viswanathan et al.	
	AZ*	US-5,220,590	06-15-1993	Bruning et al.	
	AA1*	US-5,315,629	05-24-1994	Jewell et al.	
	AB1*	US-5,353,322	10-04-1994	Bruning et al.	
	AC1*	US-5,410,434	04-25-1995	Shafer	
	AD1*	US-5,477,304	12-19-1995	Nishi et al.	
	AE1*	US-5,488,229	01-30-1996	Elliott et al.	
	AF1*	US-5,515,207	05-07-1996	Foo	
	AG1*	US-5,636,066	06-03-1997	Takahashi et al.	
	AH1*	US-5,650,877	07-22-1997	Phillips, Jr. et al.	
	AI1*	US-5,652,679	07-29-1997	Freeman et al.	
	AJ1*	US-5,686,728	11-11-1997	Shafer	
	AK1*	US-5,717,518	02-10-1998	Shafer et al.	
	AL1*	US-5,729,376	03-17-1998	Hall et al.	

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		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	MM-DD-YYYY			
	BG	EP-0951054-A1	10-20-1999	Nippon Kogaku Kk		
	BH	EP-0962830	12-08-1999	NIPPON KOGAKU KK		✓
	BI	EP-1061396-A2	12-20-2000	Canon Kk		
	BJ	EP-1059550-A1	12-13-2000	Nippon Kogaku Kk		
	BK	EP-1069448	01-17-2001	Nippon Kogaku Kk		
	BL	EP-1089327-A1	04-04-2001	Nippon Kogaku Kk		

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		Number-Kind Code ² (if known)			
	AM1*	US-5,734,496	03-31-1998	Beach et al.	
	AN1*	US-5,802,335	09-01-1998	Sturles et al.	
	AO1*	US-5,805,346	09-08-1998	Tomimatsu et al.	
	AP1*	US-5,805,365	09-08-1998	Sweatt	
	AQ1*	US-5,815,310	09-29-1998	Williamson et al.	
	AR1*	US-5,861,997	01-19-1999	Takahashi	
	AS1*	US-5,917,879	06-29-1999	Mashima et al.	
	AT1*	US-5,956,192	09-21-1999	Williamson et al.	
	AU1*	US-5,969,441	10-19-1999	Loopstra et al.	
	AV1*	US-5,989,310	12-07-1999	Shafer et al.	
	AW1*	US-6,033,079	03-07-2000	Hudyma	
	AX1*	US-6,064,516	05-16-2000	Schuster et al.	Corresponds to DE 19633128
	AY1*	US-6,097,537	08-01-2000	Takahashi et al.	
	AZ1*	US-6,169,627	01-02-2001	Schuster et al.	
	AA2*	US-6,169,637	01-02-2001	Tsunashima et al.	
	AB2*	US-6,172,825	01-09-2001	Takahashi et al.	
	AC2*	US-6,188,513	02-13-2001	Hudyma et al.	
	AD2*	US-6,195,213	02-27-2001	Omura et al.	
	AE2*	US-6,213,610	04-10-2001	Takahashi et al.	

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		Country Code ² Number ³ Kind Code ⁴ (if known)			
	BM	EP-1098215-A1	05-09-2001	Zeiss Carl et al.	
	BN	EP-1318425-A2	06-11-2003	Nippon Kogaku Kk	
	BO	EP-1336887-A1	08-20-2003	Nippon Kogaku Kk	
	BP	EP-1480065-A2	11-24-2004	Canon Kk	
	BQ	EP-1635382-A1	03-15-2006	Nippon Kogaku Kk	
	BR	GB-2146454-A	04-17-1985	Gen Signal Corp	

Examiner Signature	Date Considered
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		Art Unit	2873		
		Examiner Name	E. A. Lester		
Sheet	4	of	14	Attorney Docket Number	01641/0204258-US0

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		Number-Kind Code ² (if known)			
	AF2*	US-6,259,510	07-10-2001	Suzuki et al.	
	AG2*	US-6,262,845	07-17-2001	Sweatt	
	AH2*	US-6,285,737	09-04-2001	Sweatt et al.	
	AI2*	US-6,353,470	03-05-2002	Dinger et al.	
	AJ2*	US-6,426,506	07-30-2002	Hudyma	
	AK2*	US-6,473,243	10-29-2002	Omura et al.	
	AL2*	US-6,597,498	07-22-2003	Schuster et al.	
	AM2*	US-6,600,608	07-29-2003	Shafer et al.	
	AN2*	US-6,631,036	10-07-2003	Schuster et al.	
	AO2*	US-6,636,350-A ¹	10-21-2003	Shafer et al.	
	AP2*	US-6,750,948	06-15-2004	Omura et al.	
	AQ2*	US-6,757,051	06-29-2004	Takahashi et al.	
	AR2*	US-6,816,320	11-09-2004	Wada et al.	
	AS2*	US-6,822,727	11-23-2004	Shima et al.	
	AT2*	US-6,829,099	12-07-2004	Kato et al.	
	AU2*	US-6,842,298	01-11-2005	Shafer et al.	
	AV2*	US-6,873,476	03-29-2005	Shafer	
	AW2*	US-6,912,042	06-28-2005	Shafer	
	AX2*	US-6,930,758	08-16-2005	Schuster et al.	

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		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
	BS	JP-5175098-A	07-13-1993	Nippon Kogaku Kk		✓
	BT	JP-06053120-A	02-25-1994	Nippon Kogaku Kk		✓
	BU	JP-6188169-A	07-08-1994	Canon Kk		✓
	BV	JP-8166542-A	06-25-1996	Nisshin Koki Kk		✓
	BW	JP-8330220-A	12-13-1996	Nippon Kogaku Kk		✓
	BX	JP-9148241-A	06-06-1997	Canon Kk		✓

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		Number-Kind Code ² (if known)			
	AY2*	US-6,995,886	02-07-2006	Hendriks et al.	
	AZ2*	US-6,995,918	02-07-2006	Terasawa et al.	
	AA3*	US-7,030,965	04-18-2006	Takahashi et al.	
	AB3*	US-7,075,726	07-11-2006	Terasawa et al.	
	AC3*	US-7,079,314	07-18-2006	Suenaga et al.	
	AD3*	US-7,085,075	08-01-2006	Mann et al.	
	AE3*	US-7,092,168	08-15-2006	Terasawa et al.	
	AF3*	US-7,187,503	03-06-2007	Rostalski et al.	
	AG3*	US-7,190,530	03-13-2007	Mann et al.	
	AH3*	US-7,218,445-A1	05-15-2007	Shafer et al.	
	AI3*	US-7,224,520	05-29-2007	Mitchell	
	AJ3*	US-7,237,915	07-03-2007	Hudyma	
	AK3*	US-7,239,453	07-03-2007	Terasawa et al.	
	AL3*	US-20010019454	09-06-2001	Tadic-Galeb et al.	
	AM3*	US-20020024741-A1	02-28-2002	Terasawa et al.	
	AN3*	US-20020176063	11-28-2002	Omura	
	AO3*	US-20030011755	01-16-2003	Omura et al.	
	AP3*	US-20030011894	01-16-2003	Schuster	
	AQ3*	US-20030174301	09-18-2003	Imanishi	

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		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
	BY	JP-10163099-A	06-19-1998	Nippon Kogaku Kk		✓
	BZ	JP-10214783-A	08-11-1998	Nippon Kogaku Kk		✓
	BA1	JP-10284408-A	10-23-1998	Nippon Kogaku Kk		✓
	BB1	JP-10303114-A	11-13-1998	Nippon Kogaku Kk		✓
	BC1	JP-2001228401-A	08-24-2001	Canon Kk		✓
	BD1	JP-2002208551-A	07-26-2002	Nippon Kogaku Kk		✓

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	AR3*	US-20030197922	10-23-2003	Hudyma	
	AS3*	US-20030197946	10-23-2003	Omura	
	AT3*	US-20030234912	12-25-2003	Omura	
	AU3*	US-20030234992	12-25-2003	Shafer	
	AV3*	US-20040012866	01-22-2004	Mann et al.	
	AW3*	US-20040075895	04-22-2004	Lin	
	AX3*	US-20040130806	07-08-2004	Takahashi	
	AY3*	US-20040160677	08-19-2004	Epple et al.	
	AZ3*	US-20040190151	09-30-2004	Krahmer et al.	Corresponds to DE10123725
	AA4*	US-20040207928	10-21-2004	Schultz et al.	
	AB4*	US-20040240047	12-02-2004	Shafer et al.	
	AC4*	US-20050036213	02-17-2005	Mann et al.	
	AD4*	US-20050082905	04-21-2005	Gronau et al.	
	AE4*	US-20050179994	08-18-2005	Webb	
	AF4*	US-20050190435	09-01-2005	Shafer et al.	
	AG4*	US-20050248856	11-10-2005	Omura et al.	
	AH4*	US-20060066962	03-30-2006	Totzeck et al.	
	AI4*	US-20060077366	04-13-2006	Shafer et al.	
	AJ4*	US-20060114445	06-01-2006	Ebihara	

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	BF1	JP-2002372668-A	12-26-2002	Nippon Kogaku Kk		✓
	BG1	JP-2003114387	04-18-2003	Omura Yasuhiro		✓
	BH1	JP-2003307660-A	10-31-2003	Nippon Kogaku Kk		✓
	BI1	JP-2004333761-A	11-25-2004	Nippon Kogaku Kk		✓
	BJ1	JP-2004317534-A	11-11-2004	Nippon Kogaku Kk		✓

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	AK4*	US-20060119750	06-08-2006	Eppe et al.	
	AL4*	US-20060132739	06-22-2006	Ebihara	
	AM4*	US-20060132740	06-22-2006	Ebihara	
	AN4*	US-20060198018	09-07-2006	Shafer et al.	
	AO4*	US-20060244936	11-02-2006	Schuster	
	AP4*	US-20060256447	11-16-2006	Dodoc	
	AQ4*	US-20070037079	02-15-2007	Omura	
	AR4*	US-20070064214	03-22-2007	Ebihara	
	AS4*	US-20070091451	04-26-2007	Schuster	
	AT4*	US-20070109659	05-17-2007	Rostalski et al.	
	AU4*	US-20070165198	07-19-2007	Kneer et al.	
	AV4*	US-20070211234	09-13-2007	Ebihara	
	AW4*	US-20080037111	02-14-2008	Shafer et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
	BK1	JP-2005003982-A	01-06-2005	Nippon Kogaku Kk		✓
	BL1	KR-102006018869	03-02-2006	Nippon Kogaku Kk		✓
	BM1	WO-9205462-A2	04-02-1992	Optics & Vision Ltd		
	BN1	WO-9406047	03-17-1994	Optics & Vision Limited et al.		
	BO1	WO-9828665-A1	07-02-1998	Philips Electronics Nv et al.		
	BP1	WO-9926097-A1	05-27-1999	Koninkl Philips Electronics Nv et al.		

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Substitute for form 1449/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>				Application Number	10/596,626-Conf. #8534
				Filing Date	September 15, 2006
				First Named Inventor	Karl-Heinz Schuster
				Art Unit	2873
				Examiner Name	E. A. Lester
Sheet	13	of	14	Attorney Docket Number	01641/0204258-USO

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	CA	US. Appl. No. 60/632,530, filed Dec. 01, 2004, Weippert et al.	
	CB	M. Switkes et al., Resolution Enhancement of 157-nm Lithography by Liquid Immersion, Proc. SPIE vol. 4691, Optical Microlithography XV, pp. 459-465, Jul. 2002.	
	CC	Tomoyuki Matsuyama et al., "Microlithographic Lens for DUV Scanner," SPIE vol. 4832, Dec. 2003, pp. 170-174.	
	CD	Tomoyuki Matsuyama et al., "High NA and Low Residual Aberration Projection Lens for DUV Scanner," SPIE, vol. 4691 (2002), pp. 687-695.	
	CE	Ulrich, W. et al., "Trends in Optical Design of Projection Lenses for UV-and EUV-Lithography," Proc. Of SPIE vol. 4146 (2000).	
	CF	Glatzel, E., "New Lenses for Microlithography," SPIE vol. 237 (1980), pp. 310-320.	
	CG	J. J. Shaffer et al., "Effect of Thermal Cycling on Dimensional Stability of Zerodur and ULE", Applied Optics, vol. 23, No. 14, Sep. 1, 1984.	
	CH	Jacobs et al., "Expansion hysteresis upon thermal cycling of Zerodur", Applied Optics, vol. 23, No. 17, Sep. 01, 1984.	
	CI	Lindig et al., "Thermal expansion and length stability of Zerodur in dependence on temperature and time", Applied Optics, vol. 24, No. 20, Oct. 15, 1985.	
	CJ	M. H. Freeman, "Innovative Wide-Field Binocular Design", OSA Proceedings of the International Optical Design Conference, 1994, pp. 389-393, vol. 22.	

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				First Named Inventor	Karl-Heinz Schuster
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				Examiner Name	E. A. Lester
Sheet	14	of	14	Attorney Docket Number	01641/0204258-US0

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	CK	Tomoyuki Matsuyama et al., "Nikon Projection Lens Update", Proceedings of SPIE, 2004, vol. 5377, No. 65.	
	CL	Donald DeJager, "Camera viewfinder using tilted concave mirror erecting elements", International Lens Design Conference (OSA), SPIE, 1980, pp. 292-298, vol. 237.	

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